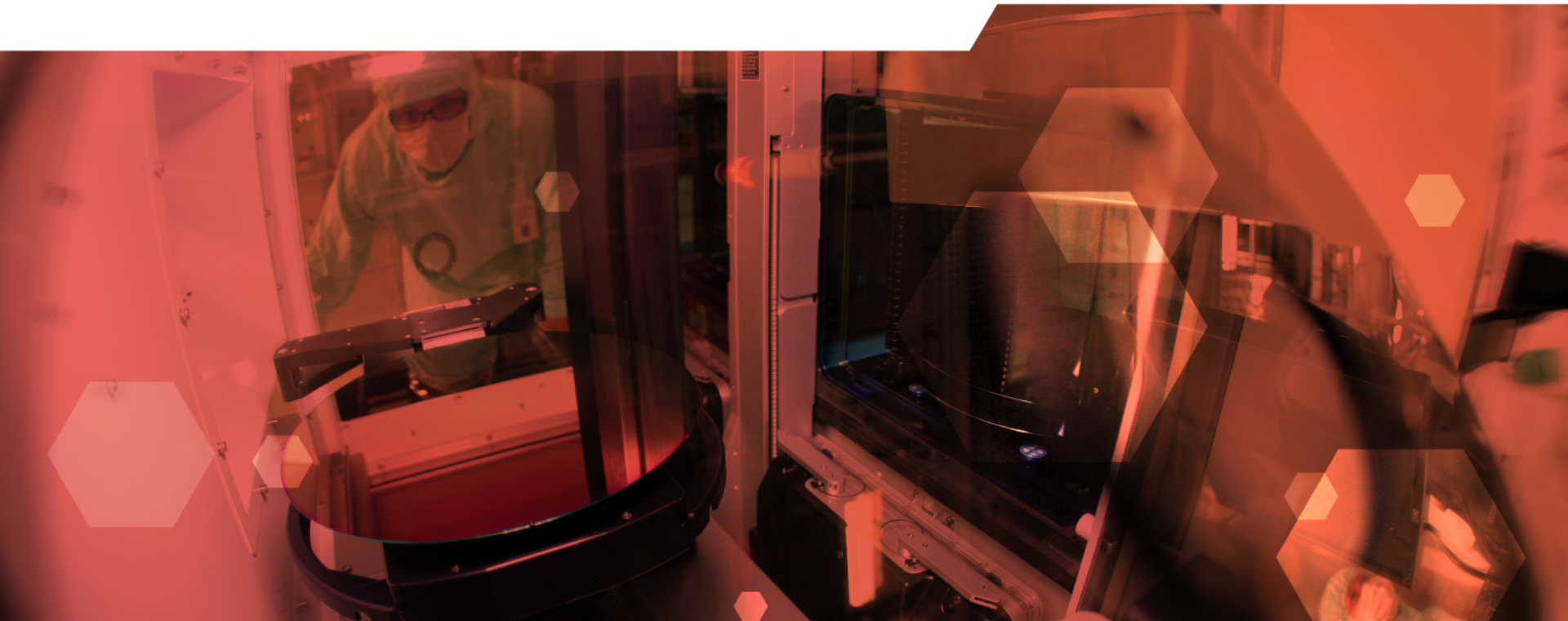


SEMI Staff Report

July 2017

PIC NA TC Chapter



SEMI Global 2017 Calendar of Events

Event Name	Event Details
SEMICON[®] WEST	July 11-13 San Francisco, CA
SEMICON[®] TAIWAN	September 13-15 Taipei, Taiwan
 PV Taiwan Taiwan Int'l Photovoltaic Exhibition	September 18-20 Taipei, Taiwan
SEMICON[®] EUROPA	November 14-17 Munich, Germany
SEMICON[®] JAPAN	December 13-15 Big Sight Tokyo, Japan

Standards Meetings at SEMICON West 2017

Sunday	Monday	Tuesday	Wednesday	Thursday	Friday	Saturday
9	10	11	12	13	14	15
	NARSC		3DS-IC	ISC		
		EH&S				
	Facilities & Gases			HB-LED		
	Information & Control					
	Liquid Chemicals					
				MEMS/NEMS		
		Metrics				
		Microlithography				
			PV Materials			
			Physical Interfaces & Carriers			
	Silicon Wafer					
	Traceability					

**Schedule
at-a-glance**



**San Francisco
Marriott Marquis
Hotel**

Upcoming NA Meetings

Event Name	Event Type	Date / Venue
NA Standards Fall 2017 Meetings	Standards Meetings	November 6-9, 2017 SEMI HQ in Milpitas, California
NA Standards Spring 2018 Meetings	Standards Meetings	April 2-5, 2018 SEMI HQ in Milpitas, California
SEMICON West 2018	Standards Meetings	July 10-12, 2018 San Francisco, California

2017 Critical Dates for SEMI Standards Ballots

2017	Ballot Submission Deadline	Voting Opens	Voting Closes
Cycle 6	Jul 21	Aug 1	Aug 31
Cycle 7	Aug 18	Sep 1	Oct 2
Cycle 8	Oct 13	Oct 27	Nov 27
Cycle 9	Nov 16	Nov 29	Dec 29

<http://www.semi.org/en/Standards/Ballots>

SEMI Standards Publications

Cycle	New	Revised	Reapproved	Withdrawn
March 2017	0	16	11	0
April 2017	0	6	0	0
May 2017	0	4	6	0
June 2017	2	4	0	0

- Total SEMI Standards in portfolio: 974
 - Includes 191 Inactive Standards

GTC Charter & Scope Review

- Problem Statement
 - Majority of GTCs have defined charter but many don't have distinct Scope
 - It is stipulated in the Regulations that each GTC ought to have a distinct charter and scope. (See Regulations ¶5.7.3.2, §6.2)
 - As charter is often very generic (e.g., The XXXGTC discusses and creates consensus-based specifications and guides that promote mutual understanding and improved communication between users and suppliers of XXXX), it may not be useful to decide if the TF is within the scope of GTC or judge if a technical area proposal for installation of new GTC is really new.
 - Status as of today...
 - SEMI Website publishes charter of GTC
 - <http://downloads.semi.org/web/wstdsbal.nsf/StdCharters>
 - Only a couple of GTCs clearly define scope while most of them define its Standards' scopes or at least include scope description in its charter.

GTCs Charter - Scope Table as of Today

GTC	CHARTER	SCOPE
3DS-IC	X	Unclear
Assembly & Packaging	J(=global?)	x (included in the Charter)
Automated Test Equipment	X	x (included in the Charter)
Automation Technology	X	X
Compound Semiconductor Materials	x(only the Scope is defined in the Charter)	x (included in the Charter)
EH&S	X	x (defined, as part of the Charter)
Facilities	X	x (defined, as part of the Charter)
FPD Materials & Components	X	X
FPD Metrology	X	X
Gas	X	x (defined, as part of the Charter)

GTCs Charter - Scope Table as of Today

GTC	CHARTER	SCOPE
HB-LED	X	X
Information & Control	X	x (defined, as part of the Charter)
Liquid Chemicals	X	x (defined, as part of the Charter)
MEMS / NEMS	X	Undefined
Metrics	X	x (defined, as part of the Charter)
Micropatterning	X	Undefined
Photovoltaic	X	X
Photovoltaic (PV) - Materials	X	X
Physical Interfaces & Carriers	X	x (defined, as part of the Charter)
Silicon Wafer	X	x (defined, as part of the Charter)
Traceability	X	X

PIC GTC

- Current Charter

- To explore, evaluate, and formulate consensus-based standards and supporting documents that through voluntary compliance will enhance the manufacturing capability of the semiconductor industry.
- Its **scope** is limited to interfaces between and functions of mechanical and electrical equipment sub-systems; and to material movement integration, including substrate support and containment structures.

NOTE: The Physical Interfaces & Carriers Committee was previously known as the Physical Interfaces Committee.

- Current Scope

- Defined as part of Charter

Requirements/Process Reminders for TC Chapter Meetings [1/2]

- Standards Document Development Project Period
 - Project period shall not exceed 3 years (Regs 8.3.2)
 - SNARF approval to TC Chapter approval
 - If document development activity is found to be continuing, but cannot be completed with the project period, TC Chapter may grant one-year extension at a time, as many times as necessary.
 - The TC Chapter should review the expiration dates for all applicable SNARFs at each TC Chapter meeting. (PM Note 10)
- SNARF Review Period
 - A submitted SNARF for a new, or for a major revision to an existing, Standard or Safety Guideline is made available to all members of a TC Chapter's parent global technical committee for two weeks for their review and comment. (Regs 8.2.1)
 - If the SNARF is submitted at a TC Chapter meeting, the committee can review and approve, but the SNARF will need to be distributed for two weeks and then approved via GCS.
- SNARF & TFOF Form



Microsoft Word
17 - 2003 Document



Microsoft Word
17 - 2003 Document

Requirements/Process Reminders for TC Chapter Meetings [2/2]

- Procedures for Correcting Nonconforming Titles of Published Standards Document (PM Appendix 4)
 - Some Standards qualify for a special procedure where a line item change can be used to correct the titles. Otherwise, the corrective action will likely require a major revision.
 - Use of PIP form is allowed to correct title if all of the following conditions are met:
 - Standards having only one Subtype
 - Changes either Specifications to Specification or Test Methods to Test Method
 - No concomitant text change is required
 - Approved by at least one co-chair of the TC Chapter
 - Example:
 - SEMI F69-1213, Test Method **s** for Transport and Shock Testing of Gas Delivery Systems

Nonconforming Titles

(See PM Appendix 4)

- SEMI E152-0214, Mechanical Specification of EUV Pod for 150 mm EUVL Reticles
- SEMI E154-0814, Mechanical Interface Specification for 450 mm Load Port
 - Originated in NA
 - Last reviewed in Japan
- SEMI E158-0314, Mechanical Specification for Fab Wafer Carrier Used to Transport and Store 450 mm Wafers (450 FOUP) and Kinematic Coupling
- SEMI E159-0314, Mechanical Specification for Multi Application Carrier (MAC) Used to Transport and Ship 450 mm Wafers

5 Year Review

- SEMI E73-0301 (Reapproved 0413), Specification for Vacuum Pump Interfaces - Dry Pumps
- SEMI E74-0301 (Reapproved 0413), Specification for Vacuum Pump Interfaces - Turbomolecular Pumps
- SEMI E85-1108 (Reapproved 0513), Specification for Physical AMHS Stocker to Interbay Transport System Interoperability

SNARF 3 year status

TC Chapter may grant a one-year extension

- None

Thank you

SNARF(s) Approved by GCS in between TC Chapter Meetings